Date Mailed: 27 October 2003

FORM 1449 INFORMATION DISCLOSURE STATEMENT IN AN APPLICATION (Use several sheets if necessary)	Docket Number: 9997.69US01	Application Number: 10/613,260
	Applicant: MANHAEVE et al.	
	Filing Date: 3 July 2003	Group Art Unit: ~~2858~~ 2829

U.S. PATENT DOCUMENTS						
EXAMINER INITIAL	DOCUMENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	5 818 268	6 Oct. 1998	KIM et al.			
	6 414 511 B1	2 July 2002	JANSSEN et al.			
	5 914 615	22 June 1999	CHESS			
	5 483 170	9 Jan. 1996	BEASLEY et al.			

FOREIGN PATENT DOCUMENTS							
	DOCUMENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
	EP 0 811 850 ✓	10 Dec. 1997	EPO				
	EP 0 386 804 ✓	12 Sept. 1990	EPO				
	EP 0 672 911 ✓	20 Sept. 1995	EPO				
	WO 98/15844 ✓	16 April 1998	WIPO				
	EP 1 107 013 ✓	13 June 2001	EPO				

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)	
✓	STRAKA et al. "A fully digital controlled off-chip I_{DDQ} measurement unit". Automation and Test in Europe, 1998. Proceedings Paris, France, Feb. 1998, Los Alamitos, CA, *IEEE Comput. Soc, US*, pp. 495-500 (23 Feb. 1998).
✓	SU et al. "Transient power supply current monitoring-a new test method for CMOS VLSI circuits". *Journal of Electronic Testing: Theory and Applications*, Vol. 6, No. 1, pp. 23-43 (1995).
✓	EICHENBERGER et al. " On Charge Injection in Analog MOS Switches and Dummy Switch Compensation Techniques". *IEEE Transactions on Circuits and Systems*, Vol. 37, No. 2, pp. 256-264 (Feb. 1990).
✓	EICHENBERGER et al. "Dummy Transistor Compensation of Analog MOS Switches". *IEEE Journal of Solid-State Circuits*, Vol. 24, No. 4, pp. 1143-1146 (August 1989).

EXAMINER	DATE CONSIDERED 12/06/04

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form for next communication to the Applicant.